

# WEST Search History

DATE: Thursday, February 20, 2003

## Set Name Query

side by side

## Hit Count Set Name

result set

*DB=USPT,PGPB,JPAB,EPAB,DWPI,TDBD; PLUR=YES; OP=OR*

|    |  |     |    |
|----|--|-----|----|
| L4 | ((void\$1 or break\$5) with wir\$3) same (test adj structure\$1)                 | 8   | L4 |
| L3 | L2 and (void\$1 or break\$5)   | 195 | L3 |
| L2 | semiconductor and ((test\$3 or inspect\$3) with wiring) and tap\$4 and resist\$6 | 434 | L2 |
| L1 | (stress adj migration adj void\$1)   | 7   | L1 |

END OF SEARCH HISTORY

# WEST Search History

DATE: Thursday, February 20, 2003

| <u>Set Name</u><br>side by side | <u>Query</u>   | <u>Hit Count</u> | <u>Set Name</u><br>result set |
|---------------------------------|--|------------------|-------------------------------|
|                                 | <i>DB=USPT,PGPB,JPAB,EPAB,DWPI,TDBD; PLUR=YES; OP=OR</i> |                  |                               |
| L1                              | (test adj structure\$1) same street\$1                   | 11               | L1                            |

END OF SEARCH HISTORY